

<b>Notice of References Cited</b>	Application/Control No. 10/537,194	Applicant(s)/Patent Under Reexamination TAKASHIMA ET AL.	
	Examiner John P. Sheehan	Art Unit 1793	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,062,905	11-1991	Tomita et al.	148/111
*	B	US-5,037,493	08-1991	Tomita et al.	148/111
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2007/074987 A1	05-2007	PCT	Bae et al.	-----
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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